



FaultDetective Explainable to a Fault, from the Design Layout to the Software

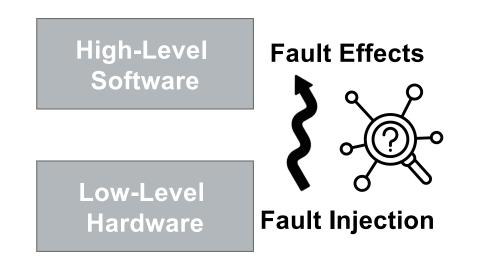
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What is Fault Root-Causing?

Explain Low-level Hardware Effects from High-level Software Observations



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Why do we care?

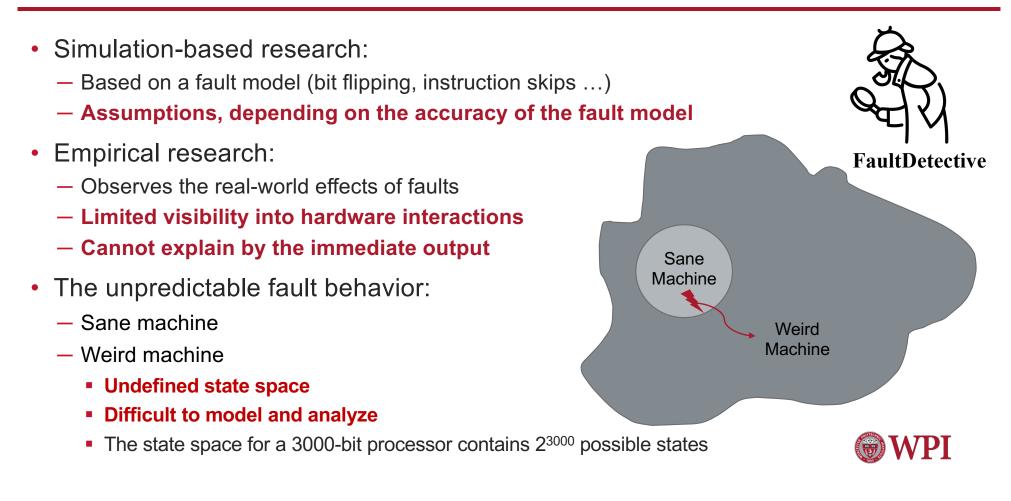
- Three fault effects: correct output, no effects, faulty output
- > Unpredictable fault behavior

Understand more than just the immediate output effects.

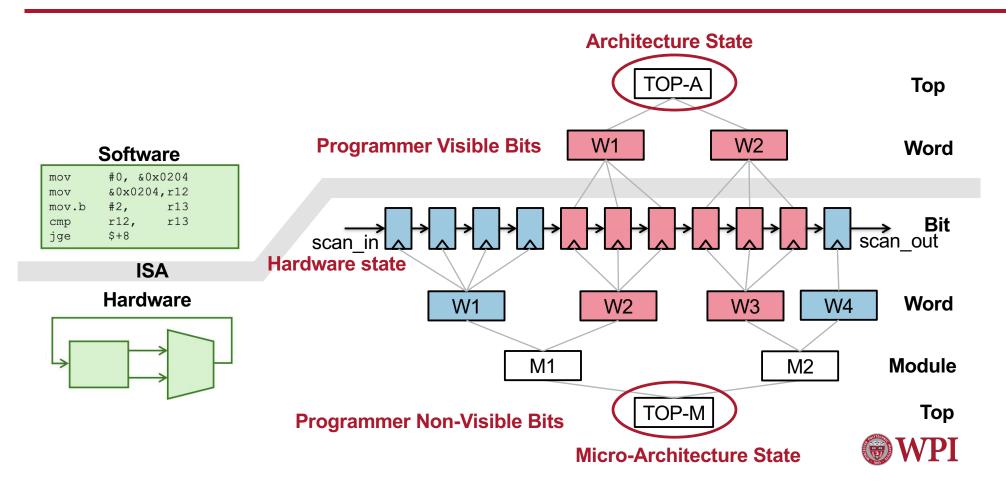
- ✓ Initial fault (the root-cause)
- ✓ Fault propagation from hardware to software
- ✓ Design improvements



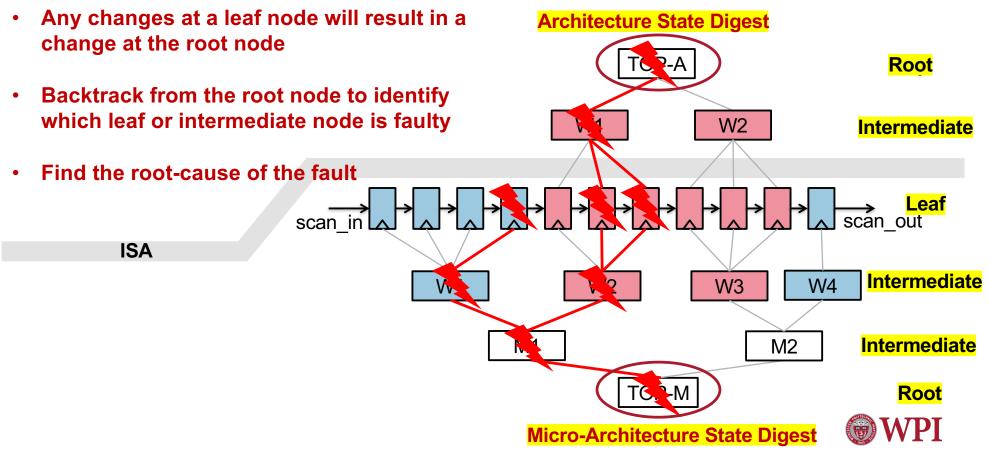
Current Research and Challenges



Architecture and Micro-Architecture States



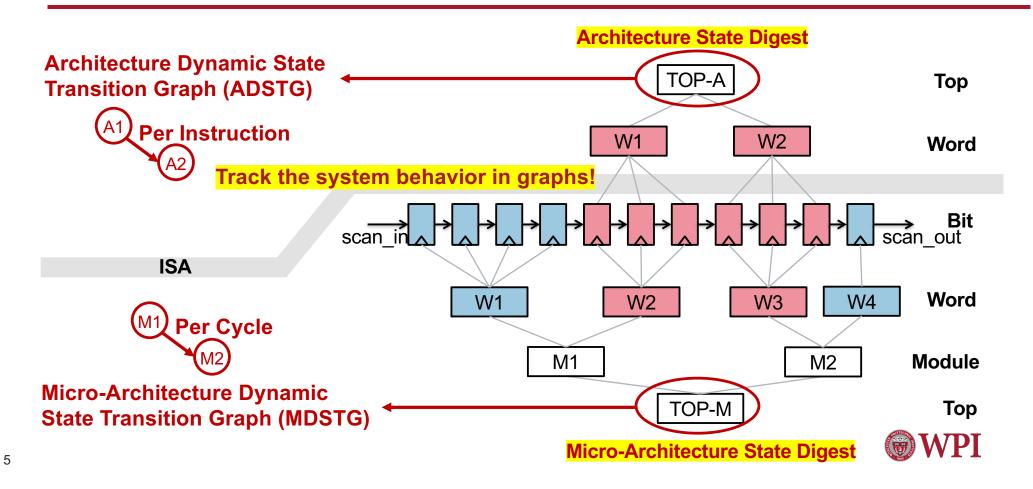
Hash Tree



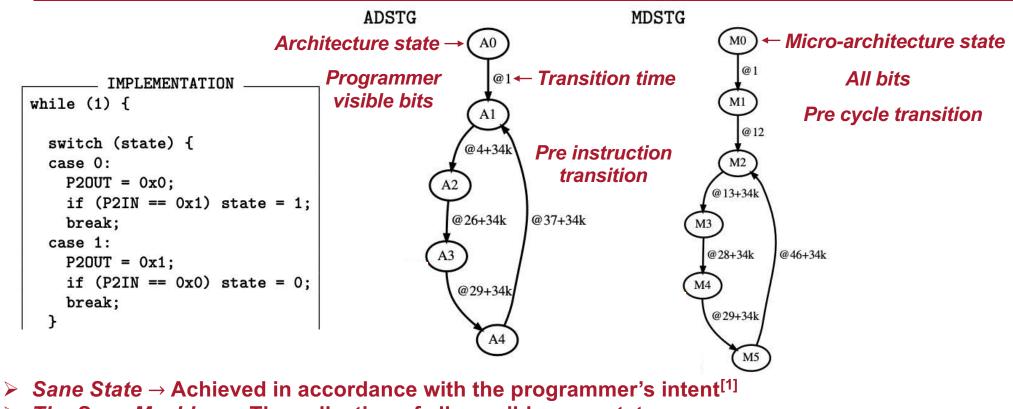
*please refer to our paper and find more details on the hash function.

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Dynamic State Transition Graph



Dynamic State Transition Graph – Before Fault



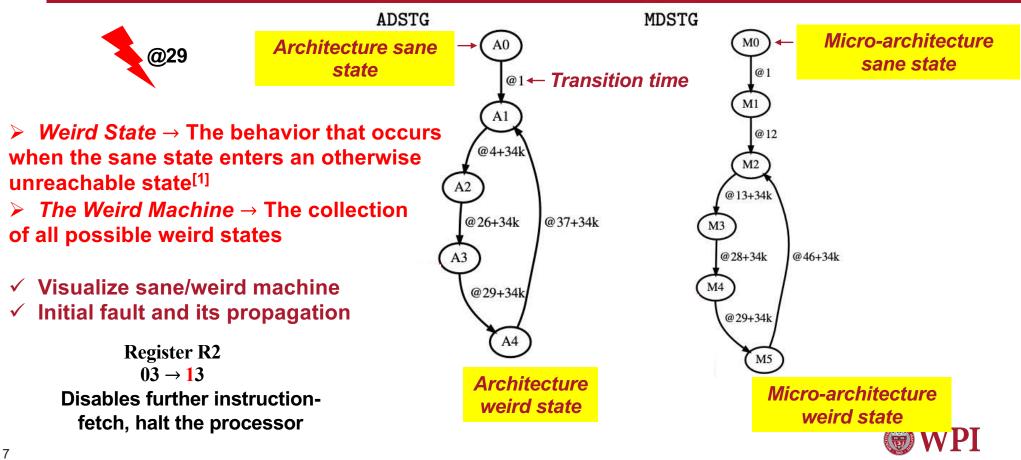
> The Sane Machine → The collection of all possible sane states

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[1] Thomas Dullien. Weird machines, exploitability, and provable unexploitability. IEEE Transactions on Emerging Topics in Computing, 8(2):391–403, 2020.

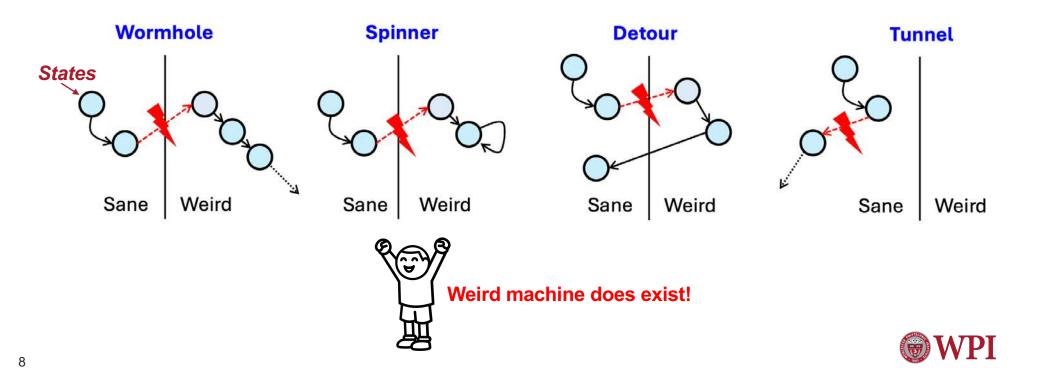
Dynamic State Transition Graph – After Fault



[1] Thomas Dullien. Weird machines, exploitability, and provable unexploitability. *IEEE Transactions on Emerging Topics III Computing*, o(2).991–403, 2020.

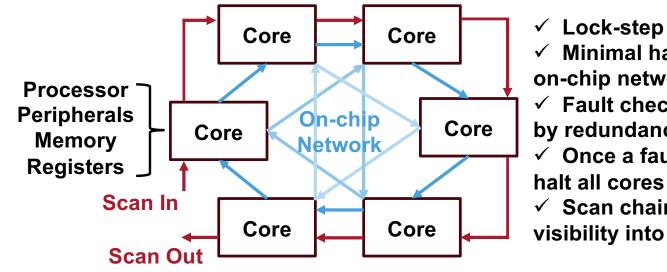
Visualized Fault Patterns

• Four fault patterns



Fault Root-Cause Analysis: FaultDetective

Hardware Redundancy + Scan Chain



Lock-step execution Minimal hardware in

on-chip network

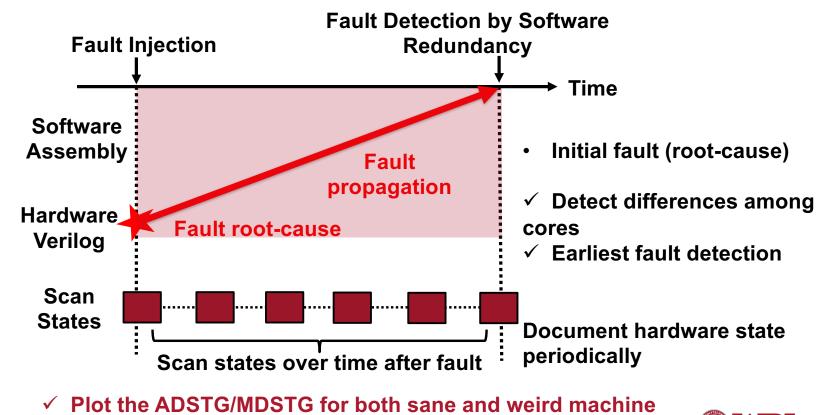
✓ Fault checking in software by redundancy

✓ Once a fault is detected,

✓ Scan chain provides visibility into all flip-flop bits



Fault Root-Cause Analysis: FaultDetective



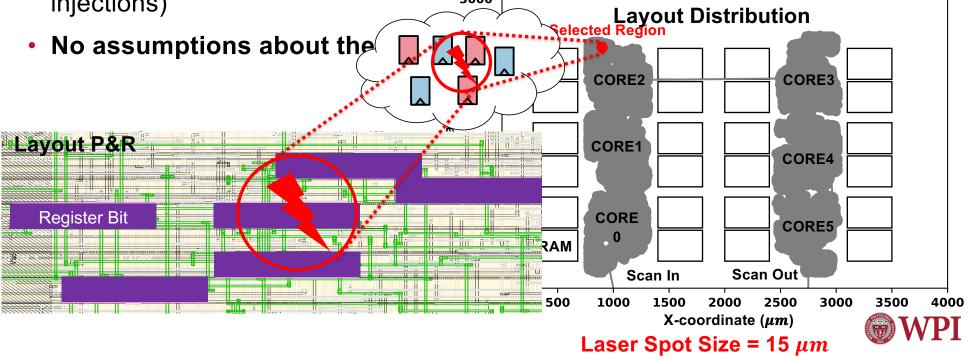
 $\checkmark\,$ Apply to both simulation and measurement fault experiments $\textcircled{\ensuremath{\mathbb{B}}} WPI$

Layout-Aware Fault Analysis in Simulation

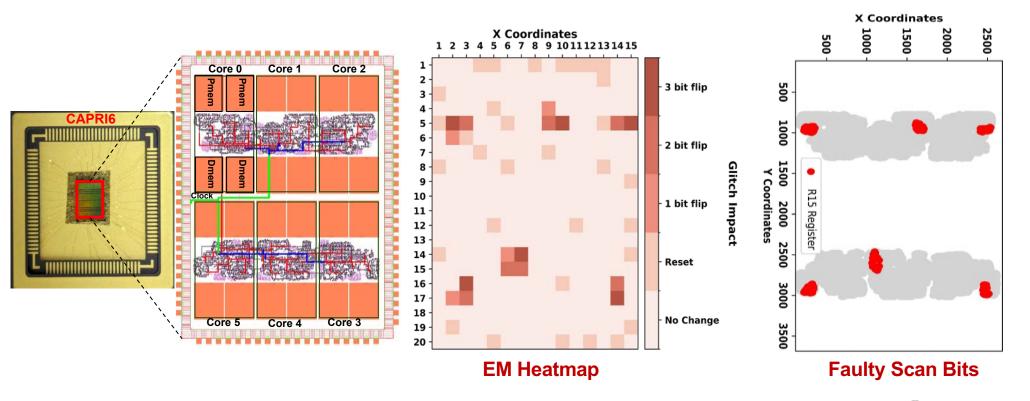
• Realization in ASIC (six-core MSP430)

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Implement real-world fault injection using layout data (laser and clock fault injections)



Measurement Result with EM-fault Injection







Any Questions?

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